# **Power MOSFET**

# 30 V, 75 A, Single N-Channel, SO-8 FL

#### **Features**

- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- Low RG
- These are Pb-Free Devices\*

#### **Applications**

- CPU Power Delivery
- DC-DC Converters and Low Side Switching

## **MAXIMUM RATINGS** ( $T_J = 25^{\circ}C$ unless otherwise stated)

	-				
Par	ameter		Symbol	Value	Unit
Drain-to-Source Vo	ltage		$V_{DSS}$	30	V
Gate-to-Source Vol	tage		$V_{GS}$	±20	V
Continuous Drain Current R <sub>θJA</sub> (Note 1)		T <sub>A</sub> = 25°C T <sub>A</sub> = 85°C	Ι <sub>D</sub>	16 11.5	Α
Power Dissipation R <sub>θJA</sub> (Note 1)		T <sub>A</sub> = 25°C T <sub>A</sub> = 85°C	P <sub>D</sub>	2.2 1.15	W
Continuous Drain Current R <sub>θJA</sub> ≤10 s		T <sub>A</sub> = 25°C T <sub>A</sub> = 85°C	Ι <sub>D</sub>	26 18.8	Α
Power Dissipation $R_{\theta JA} \leq 10 \text{ s}$	Steady State	T <sub>A</sub> = 25°C T <sub>A</sub> = 85°C	$P_{D}$	5.8 3	W
Continuous Drain Current R <sub>θJA</sub> (Note 2)		T <sub>A</sub> = 25°C T <sub>A</sub> = 85°C	I <sub>D</sub>	10.2 7.3	Α
Power Dissipation R <sub>θJA</sub> (Note 2)		T <sub>A</sub> = 25°C T <sub>A</sub> = 85°C	P <sub>D</sub>	0.88 0.46	W
Continuous Drain Current R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 25°C T <sub>C</sub> = 85°C	Ι <sub>D</sub>	75 54	Α
Power Dissipation R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 25°C T <sub>C</sub> = 85°C	P <sub>D</sub>	48 25	W
Pulsed Drain Current	t <sub>p</sub> =10 μs	T <sub>A</sub> = 25°C	I <sub>DM</sub>	225	Α
Operating Junction a	Operating Junction and Storage Temperature			-55 to +150	°C
Source Current (Body Diode)			I <sub>S</sub>	40	Α
Drain to Source dV/dt			dV/dt	6	V/ns
Single Pulse Drain-to-Source Avalanche Energy ( $V_{DD}$ = 30 V, $V_{GS}$ = 10 V, $I_{L}$ = 31 A, $L$ = 0.3 mH, $R_{G}$ = 25 $\Omega$ )			EAS	144	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

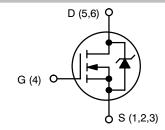
- 1. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
- 2. Surface-mounted on FR4 board using the minimum recommended pad size.



## ON Semiconductor®

#### http://onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX		
2014	5.0 mΩ @ 10 V			
30 V	8.0 mΩ @ 4.5 V	75 A		

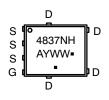


#### **N-CHANNEL MOSFET**

## MARKING DIAGRAM



SO-8 FLAT LEAD CASE 488AA STYLE 1



A = Assembly Location

Y = Year WW = Work Week ■ = Pb-Free Package

(Note: Microdot may be in either location)

## **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NTMFS4837NHT1G	SO-8 FL (Pb-Free)	1500 / Tape & Reel
NTMFS4837NHT3G	SO-8 FL (Pb-Free)	5000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

## THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	2.6	
Junction-to-Ambient - Steady State (Note 3)	$R_{ heta JA}$	56.6	°C/W
Junction-to-Ambient - Steady State (Note 4)	$R_{\theta JA}$	142	30/00
Junction-to-Ambient (t≤10 s)	$R_{ heta JA}$	21.6	

## FLECTRICAL CHARACTERISTICS (T<sub>1</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Condi	ition	Min	Тур	Max	Unit
OFF CHARACTERISTICS	•				1	1	
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /				27.5		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 24 V	T <sub>J</sub> = 25 °C T <sub>.J</sub> = 125°C			1	μΑ
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub>	, ,			10 ±100	nA
ON CHARACTERISTICS (Note 5)	'655	7DS = 3 4, 4GS	- ===			=100	117 (
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D = 250 \mu A$		1.5	2.1	2.5	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>	. GO . DO, ID - 200 M			5.7		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V to 11.5 V	I <sub>D</sub> = 30 A		3.7	5.0	
			I <sub>D</sub> = 15 A		3.7		
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 30 A		6.5	8.0	mΩ
			I <sub>D</sub> = 15 A		6.4		1
Forward Transconductance	9FS	V <sub>DS</sub> = 1.5 V, I <sub>D</sub> = 50 A			67		S
CHARGES AND CAPACITANCES	•			•		•	•
Input Capacitance	C <sub>ISS</sub>				2234	3016	
Output Capacitance	C <sub>OSS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 12 V			450	608	pF
Reverse Transfer Capacitance	C <sub>RSS</sub>				243	375	
Total Gate Charge	Q <sub>G(TOT)</sub>				15.9	23.8	
Threshold Gate Charge	Q <sub>G(TH)</sub>	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}; I_D = 30 \text{ A}$			2.8	4.3	nC
Gate-to-Source Charge	$Q_{GS}$				6.4	9.5	
Gate-to-Drain Charge	$Q_{GD}$				6.6	9.8	
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 11.5 V, V <sub>DS</sub> = 15 V; I <sub>D</sub> = 15 A			34.4	53	nC
SWITCHING CHARACTERISTICS (Note 6)	•						
Turn-On Delay Time	t <sub>d(ON)</sub>				15.2	22.8	
Rise Time	t <sub>r</sub>	$V_{GS}$ = 4.5 V, $V_{DS}$ = 15 V, $I_{D}$ = 15 A, $R_{G}$ = 3.0 $\Omega$			27.5	41.3	1
Turn-Off Delay Time	t <sub>d(OFF)</sub>				18.3	27.5	ns
Fall Time	t <sub>f</sub>				7.1	10.6	7

Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
 Surface-mounted on FR4 board using the minimum recommended pad size.

<sup>5.</sup> Pulse Test: pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2%.
6. Switching characteristics are independent of operating junction temperatures.

# **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (N	ote 6)				•	•	•
Turn-On Delay Time	t <sub>d(ON)</sub>			9.0	14	ns	
Rise Time	t <sub>r</sub>	$V_{GS}$ = 11.5 V, $V_{DS}$ = 15 V, $I_{D}$ = 15 A, $R_{G}$ = 3.0 $\Omega$			19.6		29.3
Turn-Off Delay Time	t <sub>d(OFF)</sub>				28		38.7
Fall Time	t <sub>f</sub>				4.7		7
DRAIN-SOURCE DIODE CHARACTI	ERISTICS						
Forward Diode Voltage	V <sub>SD</sub>	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 30 A	T <sub>J</sub> = 25°C		0.83	1.2	V
			T <sub>J</sub> = 125°C		0.71		
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, } dI_{S}/dt = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 30 \text{ A}$			23.5		ns
Charge Time	t <sub>a</sub>				11.3		
Discharge Time	t <sub>b</sub>				12.2		
Reverse Recovery Charge	Q <sub>RR</sub>				8		nC
PACKAGE PARASITIC VALUES							
Source Inductance	L <sub>S</sub>	- - T <sub>A</sub> = 25°C			0.93		nH
Drain Inductance	L <sub>D</sub>				0.005		1
Gate Inductance	L <sub>G</sub>				1.84		
Gate Resistance	$R_{G}$				0.9		Ω

<sup>5.</sup> Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
6. Switching characteristics are independent of operating junction temperatures.

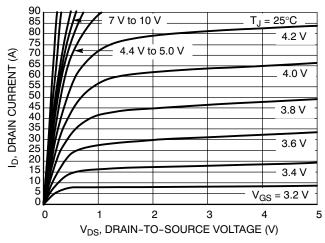


Figure 1. On-Region Characteristics

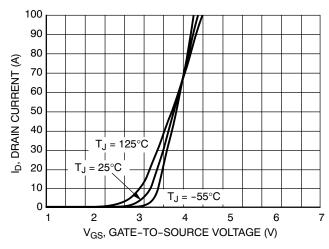


Figure 2. Transfer Characteristics

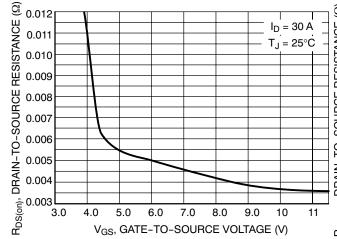


Figure 3. On-Resistance versus Gate-to-Source Voltage

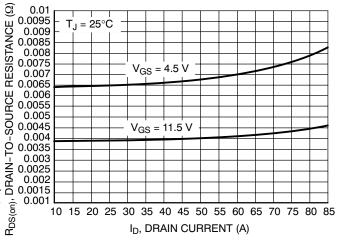


Figure 4. On-Resistance versus Drain Current and Gate Voltage

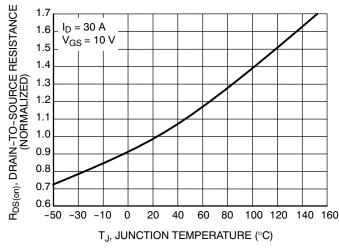


Figure 5. On–Resistance Variation with Temperature

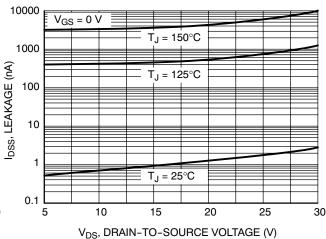


Figure 6. Drain-to-Source Leakage Current versus Voltage

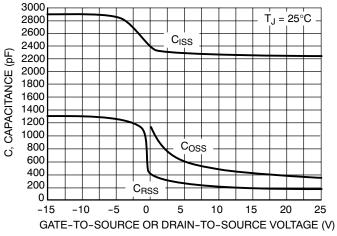


Figure 7. Capacitance Variation

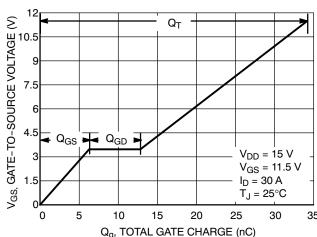


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Gate Charge

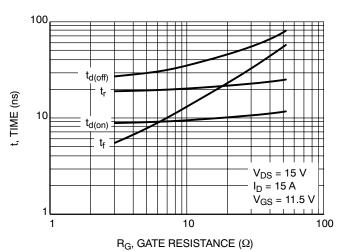


Figure 9. Resistive Switching Time Variation versus Gate Resistance

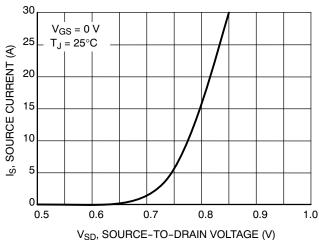


Figure 10. Diode Forward Voltage versus Current

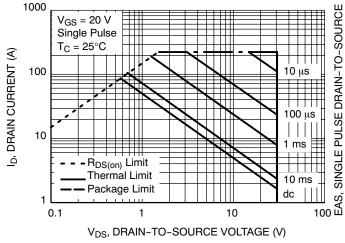


Figure 11. Maximum Rated Forward Biased Safe Operating Area

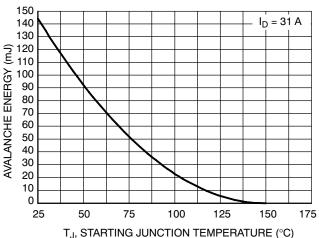


Figure 12. Maximum Avalanche Energy versus Starting Junction Temperature

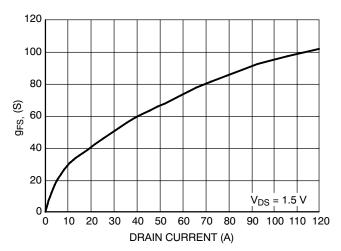
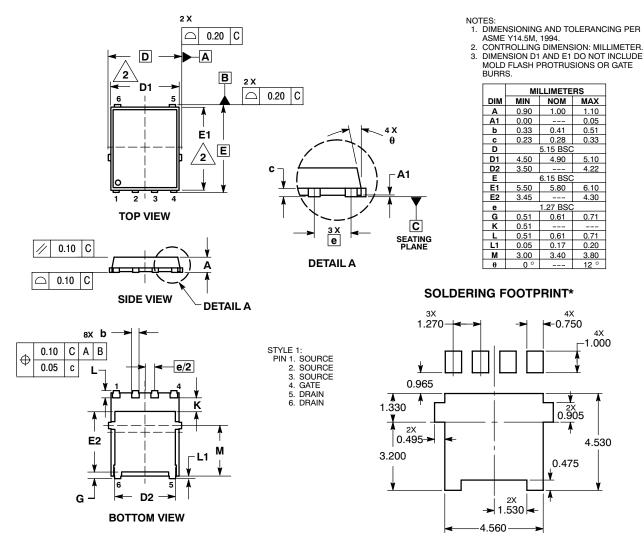


Figure 13.  $G_{FS}$  versus Drain Current

#### PACKAGE DIMENSIONS

# **DFN6 5x6, 1.27P (SO8 FL)**CASE 488AA-01 ISSUE C



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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